



2007 IEEE Instrumentation and Measurement Technology Conference
Synergy of Science and Technology in Instrumentation and Measurement
Warsaw Marriott Hotel, Warsaw, Poland, May 1-3, 2007 (Tuesday-Thursday)

CALL FOR PAPERS

The Conference focuses on all aspects of instrumentation and measurement science and technology – research, development and applications. The list of program topics includes but is not limited to:

MEASUREMENT SCIENCE & EDUCATION

Theoretical foundations
Quantities, units & standards
Calibration & self-calibration
Measurement uncertainty
Methodology of teaching

MEASUREMENT SYSTEMS

Automated test & diagnostics systems
Fault-tolerant & resilient measurement systems
Integrated & visual measurement systems
Distributed measurement systems
Autonomous measurement systems
Non-invasive measurement systems
Virtual measurement systems
Measurement microsystems
Human-computer interface

MEASUREMENT-DATA ACQUISITION

Sensors & transducers
A/D and D/A converters
Analog & mixed signal processing
Measurement signal generation
Remote measurements & telemetry

MEASUREMENT-DATA PROCESSING

Mathematical modeling of signals and systems
Data preprocessing & postprocessing
Digital signal processing
Image processing & pattern recognition
Inverse problems & signal reconstruction
Signal detection & classification
Sensor array processing
Soft computing
Measurement-data management

MEASUREMENTS OF PHYSICAL QUANTITIES

Electrical & power measurements
Dielectric & magnetic measurements
Temperature, moisture & humidity measurements
Mechanical measurements & material analysis
Optical measurements
Chemical & biological measurements

MEASUREMENT APPLICATIONS

Robotics & industrial monitoring
Automotive & transportation
Avionics & aerospace
Ships and marine technology
Environmental monitoring
Medicine & scientific research
Security & biometrics
Telecommunications

The program of IMTC 2007 will include special sessions related to hot topics such as measurements in nanotechnology, micro- and nano-optics measurements, new generations of sensors, *etc.* Moreover, IMTC 2007 will offer a day of tutorials on April 30, 2007 (Monday).

Potential authors are invited to submit extended abstracts via the IMTC website (<http://ewh.ieee.org/soc/im/imtc/imtc2007>). Each extended abstract (3 or 4 pages in English) should report results of the original research of theoretical or applied nature. It should, moreover, explain the significance of the contribution and contain a list of key references. It must be prepared according to the abstract preparation guidelines provided on the IMTC website. Check that website for detailed instructions, and follow the deadlines:

- **October 6, 2006** – for the submission of extended abstracts,
- **December 9, 2006** – for the notification of authors on the acceptance or rejection of extended abstracts,
- **March 6, 2007** – for the submission of camera-ready full-text papers.

The extended abstracts will be reviewed by the Technical Program Committee. The authors of accepted abstracts, who submit the full-text papers, will be obliged to guarantee that they register for the Conference, pay registration fees, attend the Conference, and present their papers. A submitted paper will be published in the proceedings only if it is accompanied by the registration form(s) and the full member/non-member registration fees(s) for at least one of the authors (Student or Life Member fees are not sufficient). A full registration fee covers the publication of up to two accepted papers; each additional paper under the same registration requires a publication fee of US\$ 50. The authors of papers, presented during IMTC 2007, will be allowed to submit updated and extended versions of those papers to the Special Issue of *IEEE Transactions on Instrumentation & Measurement* on IMTC 2007 to be published in 2008.

Further information

will be provided on IMTC website:
<http://ewh.ieee.org/soc/im/imtc/imtc2007>